

X RAY FLUORESCENCE SPECTROMETER/FILM THICKNESS GAGE (PROFESSIONAL TYPE) CODE XRF-PT230

MANUAL ZOOM



- Application fields: electroplating coating thickness analysis, inspection of electronic components such as connectors, fastener industry, automotive parts, hardware industry (household equipment and accessories, such as Cr/Ni/CuZn(ABS)), new energy industry (photovoltaic welding wire, etc.), thickness analysis of accessories, Ni/Cu/Ni/FendB on rubidium iron boron magnets, metal cation detection in electroplating solution, etc.
- It can detect 90 types of coating elements and be used in the analysis of 77 types of elemental composition in geology, alloys, precious metals,
- Equipped with a micro-focus X-ray generator and an advanced light path conversion focusing system, the minimum measurable area is up to 0.03mm².
- It has non-destructive manual zoom detection technology, which can perform non-destructive testing on various shaped and irregular grooved parts from 0 to 30mm.
- Equipped with Si-Pin semiconductor detector, high resolution, fast testing speed, stable data, equipped with micro-light focusing technology, ranging spot diffusion less than 10%.
- The core EFP algorithm allows for the simultaneous analysis of 23 coating and 24 elements. It can quickly, accurately, and stably analyze multiple layers and multiple elements, including the same element in different layers.
- User-friendly closed software, automatically identifies faults, provides calibration and operation steps, and avoids misoperations.

STANDARD DELIVERY

Main unit	1pc
Computer	1pc
Printer	1pc
Accessory box	1pc
Twelve element plate	1pc
Standard plate	2pcs*

OPTIONAL DELIVERY

Electroplating solution measuring cup	XRF-PT230-MC
Solution Test Membrane	XRF-PT230-SF

*Standard plate with the following ten specifications to choose from, based on demand, with two options selected

Sort	Code	Dimension
Pure element	XRF-PT230-P01	Cr, 0.15μm
	XRF-PT230-P02	Ni, 5μm
	XRF-PT230-P03	Zn, 10μm
	XRF-PT230-P04	Cu, 8μm
	XRF-PT230-P05	Ag, 0.5μm
	XRF-PT230-P06	Au, 0.05μm
Substrate coating	XRF-PT230-P07	Ni/Cu, 2μm
	XRF-PT230-P08	ZnNi/Fe, 10μm
	XRF-PT230-P09	ZnNi/Cu, 5μm/0.7μm
	XRF-PT230-P10	ZnNi/Cu, 10μm/4μm

SPECIFICATION

Coating layer analysis	Elemental analysis range	Li (3)-U (92)
	Detection limit	0.005 μ m
	Analysis thickness	0.01-80 μ m (detection limit for different elements is different)
	Repeatability	0.1 μ m (<1 μ m thin outer coating)
	Stability	0.1 μ m (<1 μ m thin outer coating)
Composition analysis	Elemental analysis range	S (16)-U (92)
	Detection limit	2ppm
	Content analysis range	2ppm~99%
	Repeatability	0.1%
	Stability	0.1%
EFP algorithm	standard configuration	
Measuring time	5~300s	
Detector	Si-Pin semiconductor detector	
X-ray source	micro-focusing X-ray tube	
Collimator	Standard: Φ 0.3mm (Φ 0.5mm, Φ 0.3mm, Φ 0.2mm, 0.1 \times 0.3mm) four collimators optional, customized acceptable	
Spot diffusivity	<10%	
Camera	1/2.7" color CCD, zoom function	
Measure distance	zoom lens 0~30mm	
Focus method	high-sensitivity lens, manual focus	
Enlargement factor	optical magnification 38~46X, digital magnification 40~200X	
Max sample height	210mm	
XY stage	manual high-precision XY stage	
Available moving range	50mm \times 50mm	
Operating environment	15~30 $^{\circ}$ C, <70%RH	
Power	AC220V, 50Hz, 95W	
Dimension (L \times W \times H)	545 \times 380 \times 435mm	
Weight	48kg	